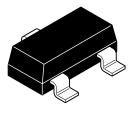


ZXMN6A07F 60V SOT23 N-channel enhancement mode mosfet

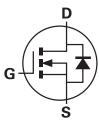
Summary

V _{(BR)DSS}	R _{DS(on)} (Ω)	I _D (A)
60	0.250 @ V _{GS} = 10V	1.4
	0.350 @ V _{GS} = 4.5V	1.2



Description

This new generation trench MOSFET from Zetex utilizes a unique structure combining the benefits of low on-state resistance with fast switching speed.



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Top view

Features

- Low on-resistance
- · Fast switching speed
- Low threshold
- SOT23 package

Applications

- DC-DC converters
- Power management functions
- Relay and solenoid driving
- Motor control

Ordering information

Device	Reel size (inches)	Tape width (mm)	Quantity per reel
ZXMN6A07FTA	7	8	3,000

Device marking

7N6

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Absolute maximum ratings

Parameter	Symbol	Limit	Unit
Drain-source voltage	V _{DSS}	60	V
Gate-source voltage	V _{GS}	± 20	V
Continuous drain current @ V_{GS} = 10V; T_{amb} =25°C ^(b)	۱ _D	1.4	А
@ V _{GS} = 10V; T _{amb} =70°C ^(b)		1.1	
@ V _{GS} = 10V; T _{amb} =25°C ^(a)		1.2	
Pulsed drain current ^(c)	I _{DM}	6.9	А
Continuous source current (body diode) ^(b)	ا _S	1	А
Pulsed source current (body diode) ^(c)	I _{SM}	6.9	А
Power dissipation at T _{amb} =25°C ^(a)	P _D	625	mW
Linear derating factor		5	mW/°C
Power dissipation at T _{amb} =25°C ^(b)	PD	806	mW
Linear derating factor		6.4	mW/°C
Operating and storage temperature range	T _j , T _{stg}	-55 to +150	°C

Thermal resistance

Parameter	Symbol	Limit	Unit
Junction to ambient	$R_{\Theta JA}$	200	°C/W
Junction to ambient	$R_{\Theta JA}$	155	°C/W

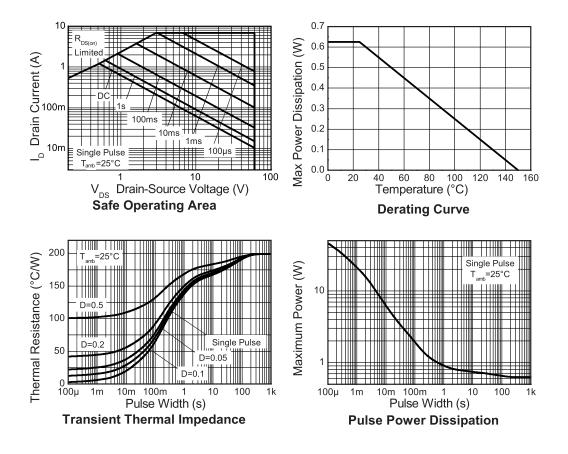
NOTES:

(a) For a device surface mounted on 25mm x 25mm FR4 PCB with high coverage of single sided 1oz copper, in still air conditions.

(b) For a device surface mounted on FR4 PCB measured at t ${\leq}5$ sec.

(c) Repetitive rating - 25mm x 25mm FR4 PCB, D=0.02, pulse width 300µs - pulse width limited by maximum junction temperature.

Thermal characteristics



Parameter	Symbol	Min.	Тур.	Max.	Unit	Conditions
Static						
Drain-source breakdown voltage	V _{(BR)DSS}	60			V	I _D = 250μA, V _{GS} =0V
Zero gate voltage drain current	I _{DSS}			1	μA	V _{DS} = 60V, V _{GS} =0V
Gate-body leakage	I _{GSS}			100	nA	$V_{GS}=\pm 20V, V_{DS}=0V$
Gate-source threshold voltage	V _{GS(th)}	1.0		3.0	V	I_D = 250 μ A, V_{DS} = V_{GS}
Static drain-source on-state	R _{DS(on)}			0.250	Ω	V _{GS} = 10V, I _D = 1.8A
resistance ^(*)				0.350	Ω	V _{GS} = 4.5V, I _D = 1.3A
Forward transconductance $(*)(\ddagger)$	9 _{fs}		2.3		S	V _{DS} = 15V, I _D = 1.8A
Dynamic ^(‡)		•				·
Input capacitance	C _{iss}		166		pF	V _{DS} = 40V, V _{GS} =0V
Output capacitance	C _{oss}		19.5		pF	f=1MHz
Reverse transfer capacitance	C _{rss}		8.7		pF	
Switching ^{(†) (‡)}		•				•
Turn-on-delay time	t _{d(on)}		1.8		ns	V _{DD} = 30V, V _{GS} = 10V
Rise time	t _r		1.4		ns	I _D = 1.8A
Turn-off delay time	t _{d(off)}		4.9		ns	$R_{G} \approx 6.0\Omega$
Fall time	t _f		2.0		ns	
Total gate charge	Qg		1.65			V _{DS} = 30V, V _{GS} = 5V I _D = 1.8A
Total gate charge	Qg		3.2		nC	V _{DS} = 30V, V _{GS} = 10V
Gate-source charge	Q _{gs}		0.67		nC	I _D = 1.8A
Gate drain charge	0 _{gd}		0.82		nC	
Source-drain diode			J			
Diode forward voltage ^(*)	V _{SD}		0.80	0.95	V	T _j =25°C, I _S = 0.45A, V _{GS} =0V
Reverse recovery time ^(‡)	t _{rr}		20.5		ns	T _j =25°C, I _F = 1.8A,
Reverse recovery charge ^(‡)	Q _{rr}		21.3		nC	di/dt=100A/μs

Electrical characteristics (at $T_{amb} = 25^{\circ}C$ unless otherwise stated)

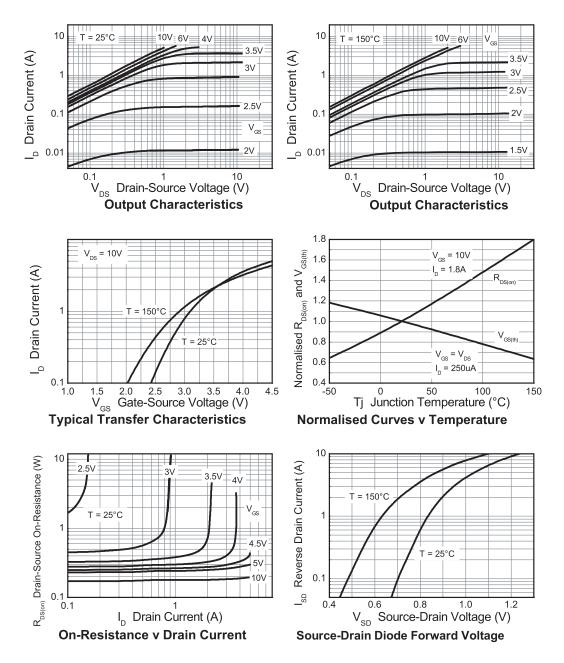
NOTES:

(*) Measured under pulsed conditions. Pulse width \leq 300 μ s; duty cycle \leq 2%.

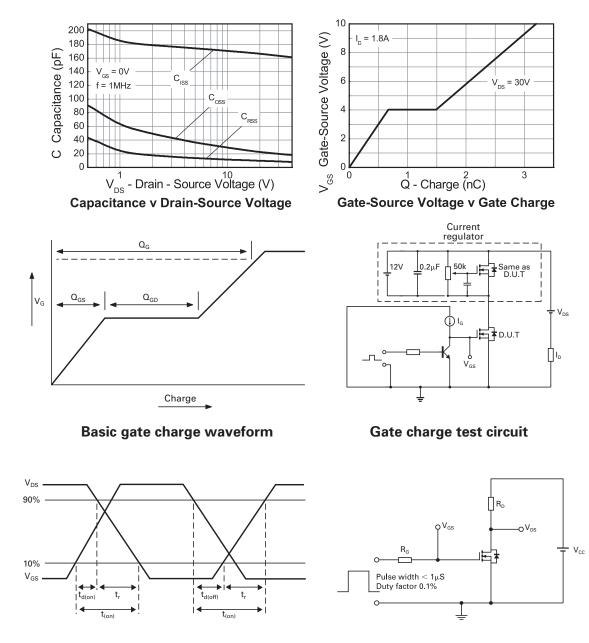
(†) Switching characteristics are independent of operating junction temperature.

(‡) For design aid only, not subject to production testing.

Typical characteristics



Typical characteristics

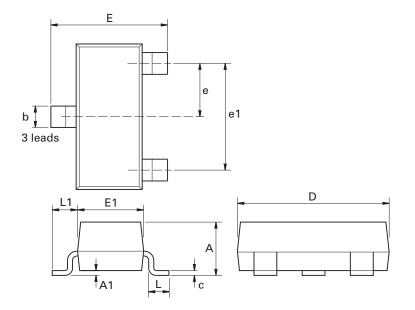


Switching time waveforms

Switching time test circuit

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Package outline - SOT23



Dim.	Millin	neters	Inc	hes	Dim.	Millimeters		Inches	
	Min.	Max.	Min.	Max.		Min.	Max.	Max.	Max.
А	-	1.12	-	0.044	e1	1.90	NOM	0.075	NOM
A1	0.01	0.10	0.0004	0.004	E	2.10	2.64	0.083	0.104
b	0.30	0.50	0.012	0.020	E1	1.20	1.40	0.047	0.055
С	0.085	0.120	0.003	0.008	L	0.25	0.62	0.018	0.024
D	2.80	3.04	0.110	0.120	L1	0.45	0.62	0.018	0.024
е	0.95	NOM	0.0375	5 NOM	-	-	-	-	-

Note: Controlling dimensions are in millimeters. Approximate dimensions are provided in inches

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"Obsolete"	Production has been discontinued
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